Search Notes					

Application No.	Applicant(s)	
10/046,196	BERN ET AL.	
Examiner	Art Unit	
Jon Chang	2623	

SEARCHED				
Class	Subclass	Date	Examiner	
382	254 228	4/12/05	OC	
		_		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	J			
			ĺ	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (printmt) IEEE Xplone intrut)	4/12/08	90	
IEEE Xplore (printunt)	4/12/05	OC	
			